

## **Search Notes**



**Application/Control No.**

09/847,606

**Examiner**

Quoc A. Tran

**Applicant(s)/Patent under  
Reexamination**

PECK ET AL.

## Art Unit

2176

SEARCHED

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PAT, US-PGPUB) see Search Histoty Printout	10/14/2005	
IEEE DataBasesee Search Histoty Printout	10/14/2005	
Stic DataBasesee Search Histoty Printout	10/14/2005	
IIP.com DataBase see Search Histoty Printout	10/14/2005	
Scirus DataBasesee Search Histoty Printout	10/14/2005	
ACM DataBasesee Search Histoty Printout	10/14/2005	

<b>Search Notes</b> 	<b>Application No.</b> <b>09/847,606</b>	<b>Applicant(s)</b> <b>PECK ET AL.</b>
	<b>Examiner</b> <b>Quoc A. Tran</b>	<b>Art Unit</b> <b>2176</b>

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Class	Subclass	Date	Examiner
715	513 520.1 521.1 522	5/21/04	CB
709	201		
	217		
	218		
	225		
345	660		
707	9,10		
↓	102		
705	10	U	↓
updated above 1/18/05 CB			
updated above 6/9/05 CB			

### INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner